

**IEC 60747-1**  
**(Second edition 2006)**

**Semiconductor devices –**  
**Part 1: General**

**CORRIGENDUM 1**

Page 39

Deletion of Annex B and replacement with the following new Annex B:

**Annex B**  
(informative)

**Clause cross-references from first edition of IEC 60747-1 (1983)**

<b>New clause (or publication)</b>	<b>Old clause</b>	<b>Old heading (in first edition 1983)</b>
A		<b>Chapter I Scope and presentation of IEC publications 747 and 748</b>
A.1	1	Publications 747
A.1	1.1	Scope
A.1	1.2	Presentation
A.2	2	Publications 748
A.2	2.1	Scope
A.2	2.2	Presentation
1		<b>Chapter II Purpose and presentation of publication 747-1</b>
1	1	Purpose
A.3	2	Presentation
A.3		<b>Chapter III Purpose, presentation and requirements on the contents of publications 747-2, 747-3, etc.</b>
A.1	1	Purpose of each part
A.3	2	Presentation of each part
A.3.1	2.1	Subdivision into chapters
A.3.2	2.2	Subdivision into device sub-categories
A.3.3	3	Requirements on the different chapters of each part
A.3.3.1	3.1	Requirements on Chapter I, General
A.3.3.1	3.1.1	Purpose
A.3.3.3 & A.3.3.4	3.2	Requirements on Chapter II, Terminology and letter symbols
A.3.3.3 & A.3.3.4	3.2.1	Purpose
A.3.3.3 & A.3.3.4	3.2.2	Validity of terms, definitions and letter symbols
A.3.3.4	3.2.3	Letter symbols
A.3.3.5	3.3	Requirements on Chapter III, Essential ratings and characteristics
A.3.3.5 - A.3.3.7	3.3.1	Purpose
A.3.3.8	3.4	Requirements on Chapter IV, Measuring methods
A.3.3.8	3.4.1	Purpose
A.3.3.9	3.5	Requirements on Chapter V, Acceptance and reliability
A.3.3.9	3.5.1	Purpose
IEC 60050-521		<b>Chapter IV Terminology, general</b>
3	1	Introduction
IEC 60050-521	2	Physical terms
IEC 60050-521	3	General terms

New clause (or publication)	Old clause	Old heading (in first edition 1983)
3.1 IEC 60748-20 3.1 IEC 60050-702 3.2 Omitted Omitted IEC 60050-521 IEC 60050-521 3.2 3.3 3.4 & IEC 60050-702 3.5 & 3.6 IEC 60050-131 IEC 60469-1 IEC 60050-521	3.1 3.2 3.3-3.6 3.7 3.8 3.9 4 5 5.1 5.2 5.3 5.4 5.5 5.6 6 7	Terms related to structure Terms related to process Anode & Cathode terminals Concepts referring to elements & circuits Concepts referring to active & passive elements, components or devices Concepts relating to components Types of devices Terms relating to ratings and characteristics Currents and voltages Temperatures Thermal characteristics Noise  Various terms Terms characterising the constant value or periodic waveforms of currents and voltages Pulse terms and definitions Input-to-output pulse switching times, general terms
4 4.1 4.2 4.2.2 4.2.3 - 4.2.7 Omitted 4.2.1 4.2.8 4.4 4.4 4.4.1- 4.4.3 4.4.4 & 4.4.5 4.4.2 4.5 Omitted 4.5.1 & 4.5.2 4.5.3 & 4.5.4 4.5.1 4.5.5 4.3 4.3 4.3	 1 2 2.1 2.2 2.3 2.4 2.5 3 3.1 3.2 3.3 3.4 4 4.1 4.2 4.3 4.4 4.5 5 5.1 5.2	<b>Chapter V Letter symbols, general</b>  Introduction Letter symbols for currents, voltages and powers Basic letters Subscripts Summary chart for current, voltage and power letter symbols Example of the application of the rules to a periodic quantity Indication of the polarity of currents and voltages Letter symbols for electrical parameters Definition Basic letters Subscripts Distinction between real and imaginary parts Letter symbols for other quantities General Times, durations Thermal characteristics and related temperatures Frequencies Sundry quantities Letter symbols for logarithmic scale units for signal ratios expressed in dB Power ratio Voltage ratio (or current ratio)
5 5.1 5.3 4.6 4.6.1 4.6.3 4.6.2 5.2.1	 1 2 3 3.1 3.1.1 3.1.2 3.2	<b>Chapter VI Essential ratings and characteristics, general</b>  Introduction Standard format for the presentation of published data Definitions Definition of maximum limit and minimum limit Algebraic convention Absolute magnitude convention Basic "rating" definitions

New clause (or publication)	Old clause	Old heading (in first edition 1983)
5.2	3.3	Definitions for rating systems
5.7	4	Definitions of cooling conditions
5.8	5	List of recommended temperatures
5.9	6	List of recommended voltages and currents
5.9	6.1	Recommended voltages
5.9	6.2	Recommended currents
(transferred to IEC 60747-3)	6.3	Preferred nominal values and limits of voltages in the E24 series for voltage-reference diodes
5.10	6.4	Preferred nominal values and limits of voltages in the E12 series for voltage-reference diodes
5.10.1	7	Mechanical ratings, characteristics and other data
5.10	7.1	Introduction
5.11	7.2	Mechanical ratings (limiting values)
5.10	7.3	Mechanical characteristics
5.11.1	7.4	Other data
Omitted	8	Standardization of the position of terminals on bases of semiconductor devices
Omitted	8.1	Position of the base, emitter and collector terminals of bipolar transistors
	8.2	Position of the terminals of high frequency bipolar transistors with four terminals
5.5	9	Colour coding of terminals for semiconductor devices
5.5	9.1	Colour coding of rectifier and signal diode terminals
5.5	9.2	Colour coding of thyristor terminals
5.5	9.3	Colour coding of transistor leads
5.12	10	General information applicable to multiple devices having a common encapsulation
5.12.1	10.1	General
5.12.2	10.2	Electrical ratings
5.12.3	10.3	Electrical characteristics
5.12.4	10.4	Thermal characteristics
5.10 & 5.11	10.5	Mechanical data
5.2.3	11	Production spread and compliance
5.2.2	12	Printed wiring and printed circuits
6		<b>Chapter VII General and reference measuring methods, general</b>
6		<i>Section 1 General measuring methods</i>
6.1	1	Introduction
6.4	2	General precautions
6.4	2.1	Protection of devices and measuring equipment
6.3 & 6.6	2.2	Accuracy of measurement
6.6	2.3	Definitions
6.6.9	2.3.3	Small signal
6.6.10	2.3.6	Pulse measurements
6		<i>Section 2. Reference measuring methods.</i>
6.1	1	Guide for reference measuring methods
6.1	1.1	Guiding principles in selecting reference methods
6.5	2	Thermal conditions for electrical reference measuring methods
6.5	2.1	Introduction
6.5	2.2	Conditions in case of negligible power dissipation in the device
6.5	2.3	Conditions in case of significant power dissipation in the device

New clause (or publication)	Old clause	Old heading (in first edition 1983)
7		<b>Chapter VIII Acceptance and reliability of discrete devices</b>
7.1		<i>Section 1. General</i>
7.1		<i>Section 2. General principles (under consideration)</i>
7.2		<i>Section 3. Electrical endurance tests</i>
7.2	1	Purpose and presentation
7.2	2	General requirements
7.2.1	2.1	Conditions for endurance tests
7.2.8	2.2	Duration of test
7.2.9 & 7.2.10	2.3	Failure-defining characteristics and measurements
7.2.10	2.4	Failure criteria
7.2.11	2.5	Precautions
(See	3	Specific requirements. General
other	3.1	List of endurance tests
relevant	3.2	Conditions for endurance tests
publication	3.3	Failure-defining characteristics and failure criteria for acceptance after endurance tests
parts)	3.4	Failure-defining characteristics and failure criteria for reliability tests
7.2.12	3.5	Procedure in case of a testing error
A.3.3.9	3.6	Information to be given in Tables I and II:
8		<b>Chapter IX Electrostatic-sensitive devices</b>
8	1	Handling precautions
8	1.1	Scope
(referred	1.2	Purpose
out	1.3	General recommendations
to other	1.4	Packaging
publications)	1.5	Transport and storage
	1.6	Handling
8.1	2	Label and symbol
8.1	2.1	Introduction
8.1	2.2	Purpose
8.1.1	2.3	Symbol
8.1.2	2.4	Label
8.1.1	2.5	Device marking
8.2	3	Test methods for electronic devices sensitive to voltage pulses of short duration